

## Laser damage resistance of optical coatings in the sub-ps regime: limitations and improvement of damage threshold

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### Optical Coating group

- Topics:
  - High performances optical interference filters
  - Innovative concepts and components
- Staff:
  - 7 permanent, 2 PhD
- Equipement:
  - 250m<sup>2</sup> clean rooms
  - 5 different machines with in situ optical monitoring: EBD, IAD, PIAD, DIBS, PARMS
  - Commercial and custom characterization systems

#### Laser Material Interaction group

- Topics:
  - Physics of laser material interactions (fs to CW)
  - Laser damage of optical components for high power applications
  - Laser processing
- Staff:
  - 6 permanent, 3 post-doc, 7 PhD students
- Equipment:
  - fs & ns LIDT measurements
  - CW laser processing
  - Commercial and custom characterization systems

## Introduction

Laser damage



![](_page_5_Picture_2.jpeg)

![](_page_6_Figure_1.jpeg)

![](_page_7_Figure_1.jpeg)

![](_page_8_Figure_1.jpeg)

![](_page_9_Figure_0.jpeg)

![](_page_9_Figure_1.jpeg)

![](_page_10_Figure_0.jpeg)

![](_page_10_Figure_1.jpeg)

![](_page_11_Figure_0.jpeg)

![](_page_11_Figure_1.jpeg)

![](_page_12_Figure_0.jpeg)

![](_page_12_Figure_1.jpeg)

![](_page_13_Figure_0.jpeg)

![](_page_13_Figure_1.jpeg)

![](_page_14_Figure_0.jpeg)

![](_page_14_Figure_1.jpeg)

![](_page_15_Figure_0.jpeg)

![](_page_15_Figure_1.jpeg)

![](_page_16_Figure_0.jpeg)

![](_page_16_Figure_1.jpeg)

![](_page_17_Figure_1.jpeg)

### Outline

Basics of short pulse laser damage process Damage resistance of optical materials Defect-induced laser damage & damage growth Improvement of laser damage resistance

## Outline

#### Basics of short pulse laser damage process

Damage resistance of optical materials Damage initiation on defects Improvement of laser damage resistance

## Basics of short pulse laser damage process Non-linear ionization

#### Ionization processes under high intensity illumination

![](_page_20_Figure_2.jpeg)

Schematic representaion of Multi-Photon Ionization, Tunnel Ionization, Impact Ionization and Electronic Avalanche

## « free » electron generation evolution during the pulse

![](_page_20_Figure_5.jpeg)

Case of  $HfO_2$  film (5.5eV), at 800nm, 100fs,  $1J/cm^2$ 

## Basics of short pulse laser damage process

1.2E17

Energy deposition in the material

#### The material becomes strongly absorbing due to free electron response

Significant absorption of the laser intensity occurs due to optical properties evolution

Intensity:

![](_page_21_Figure_4.jpeg)

1.0E17 1.0E17 1.0E17 1.0E17 1.0E17 1.0E16 1.0E16 1.0E16 1.0E-12 -5.0E-13 0.0 5.0E-13 1.0E-12 Time (s)

Evolution of the real and imaginary part of the refractive index as a function of free electron density, as described by Drude model\* Intensity as a function of time in the case of a  $Ta_2O_5$  film irradiated with a 500fs, 1030nm pulse.\*

\*L. Gallais et al., Appl. Phys. Lett. 97, 051112 (2010)

# Basics of short pulse laser damage process Damage

Damage of the material takes place when the deposited energy is sufficient to cause material modifications

![](_page_22_Figure_2.jpeg)

Calculation of energy per unit of mass deposited in a  $Sc_2O_3$  film with 500fs at 1030nm \*

Thermal or mechanical processes lead to material removal

![](_page_22_Picture_5.jpeg)

Hafnia film submitted to different fluences at 500fs/1030nm (each image is a different site)\*

\*D.B. Douti et al., Appl. Phys. A., to be published

## Basics of short pulse laser damage process Time scales

Basic processes occur at different timescales:

- Excitation
  - Absorption by free electrons in the material
    - Initial free electrons in metals
    - Free electrons created by non-linear ionisation in dielectrics
- Energy transfer
  - From electrons to lattice
  - · Heat diffusion in the material
- Response of the material
  - Phase change
  - Hydrodynamic motion, shock waves
  - Thermo-mechanical stress
- Material removal
  - Thermal or mechanical effects depending on the deposited energy, material properties and irradiation conditions

fs

ps

ns

## Basics of short pulse laser damage process Main differences with the ns regime

![](_page_24_Figure_1.jpeg)

## Basics of short pulse laser damage process

Material modifications under multiple pulses

Incubation effect related to the accumulation of electronic defects

![](_page_25_Figure_3.jpeg)

The different pathways for excitation, relaxation and trapping of electrons, characterized with a rate/lifetime Decrease of the laser damage resistance under multiple pulses

![](_page_25_Figure_6.jpeg)

 $SiO_2$  single layer, 500fs, 1030nm, multiple shots at 10Hz (Fluence set to <u>70% of the single pulse threshold</u>)

## Basics of short pulse laser damage process

Thermal effects under multiple pulses

Sub-ps Laser irradiation can locally heat the materials

![](_page_26_Figure_3.jpeg)

Finite-element simulations of the temperature rise of a protected gold mirror 2µs after a⁄dm22J90 fs, 800 nm, 10µm diameter pulse\* Heat can accumulate if the component does not have time to cool between two pulses

![](_page_26_Figure_6.jpeg)

Fluence needed to reach the melting point metallic mirrors at 1 kHz and 4.3 MHz repetition rates\*

\*B. Nagy et al., Opt. Lett. 40, 2525 (2015)

## Outline

## Basics of short pulse laser damage process Damage resistance of optical materials

Damage initiation on defects Improvement of laser damage resistance

## Damage resistance of optical materials Intrinsic Laser-Induced Damage Threshold

#### Direct dependence of LIDT on the material bandgap

![](_page_28_Figure_2.jpeg)

Clear correlation between the refractive index and LIDT AIF. 5 Al<sub>2</sub>O<sub>2</sub> Al\_O\_/AIF\_ Al<sub>2</sub>O<sub>2</sub>/SiO<sub>2</sub> HfO<sub>2</sub> HfO<sub>2</sub>/SiO<sub>2</sub> LIDT (J/cm<sup>2</sup>) R MgF<sub>2</sub> Nb<sub>2</sub>O<sub>2</sub> Nb<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> Sc<sub>2</sub>O<sub>2</sub> SiO, Ta<sub>2</sub>O<sub>5</sub> Ta<sub>2</sub>O<sub>5</sub>/SiO<sub>2</sub> TiO<sub>2</sub> Y<sub>2</sub>O<sub>3</sub> 0∟ 1.2 1.4 1.6 1.8 2.2 2.0 2.4 ZrO

LIDTs of optical materials tested in single-shot at 500 fs and 1030 nm as a function of the measured optical bandgaps\*

\*L. Gallais et al., Appl. Opt. 53, A186 (2014)

LIDTs of optical thin film materials as a function of refractive index at 1030nm\*\*

Refractive index

ZrO\_/SiO\_

\*\*B. Mangote et al., Opt. Lett. 37, 1478 (2012)

## Damage resistance of optical materials

Parametric dependence

## LIDT decreases with pulse duration for dielectrics

![](_page_29_Figure_3.jpeg)

LIDT of  $HfO_2$  single layer coatings made by Reactive Low Voltage Ion Plating or Electron Beam Deposition as a function of pulse duration, tested at 1030/1064nm\*

\*L. Gallais et al., Appl. Opt. 50, C178 (2011)

## LIDT decreases with wavelength

![](_page_29_Figure_7.jpeg)

LIDT at 100fs as a function of photon energy for different single layer coatings\*\*

\*\*L. Gallais et al., J. Appl. Phys. 117, 223103 (2015)

## Damage resistance of optical materials Multiple pulses

Excitations of mid-gap defect states at the microscopic level takes place under multiple irradiations, leading to a decrease of LIDT with increasing pulse number. This effect is strongly dependent on laser irradiation conditions and material

![](_page_30_Figure_2.jpeg)

![](_page_30_Figure_3.jpeg)

Evolution of the LIDT with the number of pluses at 500fs for <u>Silica</u> film deposited by Magnetron Sputtering\* Evolution of the LIDT with the number of pluses at 500fs for <u>Niobia</u> film deposited by Magnetron Sputtering\*

\*D.B. Douti et al., Opt. Eng. 53, 122509 (2014)

Damage resistance of optical materials Environnemental conditions

#### LIDT decrease with pressure is observed for oxides

![](_page_31_Figure_2.jpeg)

LIDT of Hafnia and Scandia at 1030nm, 500fs, in air and under vacuum (10<sup>-3</sup>mbar)\* LIDT (1030nm, 500fs) of dielectrics materials under vacuum at different temperatures\*

\*A. Hervy et al., Opt. Eng., to be published

![](_page_31_Figure_7.jpeg)

![](_page_31_Figure_8.jpeg)

## Outline

## Basics of short pulse laser damage process Damage resistance of optical materials Damage initiation on defects Improvement of laser damage resistance

#### Physical process

![](_page_33_Figure_2.jpeg)

Defect initiation

#### Macroscopic defects can induce strong local intensity enhancement

![](_page_34_Picture_3.jpeg)

Local reduction of damage threshold is observed on nodular defects

![](_page_34_Picture_5.jpeg)

FDTD simulations of  $|E|^2$ distributions for a nodular defect in a HfO<sub>2</sub>/SiO<sub>2</sub> HR mirror\* Damage initiated by a nodular defects on a HR mirror under successive irradiations at 1.45  $J/cm^{2}$ .\*

\*L. Gallais et al., Opt. Lett. 39, 1545 (2014)

#### Damage densities

#### Specific damage test

procedures can be applied to quantilfy limiting defects (damage densities / fluence)

![](_page_35_Picture_4.jpeg)

Composant optique

![](_page_35_Figure_6.jpeg)

Schematic description of a Raster scan test

Isolated damage events related to defects can occur for fluences significantly lower than the "intrinsic" LIDT

![](_page_35_Figure_9.jpeg)

Damage sites revealed by a Raster scan test on a HR MMLD mirror (1030nm, 1ps)

#### Damage growth

#### Once damage site is initiated, catastrophic damage growth limits the optics lifetime

![](_page_36_Picture_3.jpeg)

20µm

Sequence of shots on a defectinitiated damage, at a fluence set <u>to 60%</u> of the single pulse LIDT\*

\*M. Sozet et al., Opt. Lett. 41, 2342 (2016)

#### Growth can be triggered for fluences as low as 50% of the intrinsic damage threshold of the component.

![](_page_36_Figure_8.jpeg)

Evolution of the probability of growth as a function of fluence (<u>normalized with respect to the</u> <u>single pulse LIDT</u>). HR mirror, 45°, P, 1030nm, 1ps. \*

## Outline

Basics of short pulse laser damage process Damage resistance of optical materials Damage initiation on defects Improvement of laser damage resistance?

### Improvement of laser damage resistance

Materials & manufacturing

Engineered materials such as binary mixtures are interesting combinations for interference coatings used in high-power applications

![](_page_38_Figure_3.jpeg)

#### LIDT of IBS Sc<sub>2</sub>O<sub>3</sub>/SiO<sub>2</sub> mixtures compared to other coating materials\*

\*M. Mende et al., Appl. Opt. 52, 1368 (2013)

#### Reduction of defect densities related to the manufacturing process

![](_page_38_Figure_7.jpeg)

Raster scan and 1on1 measurements on different HR mirrors (1053nm, 675fs, 45° AOI, P polar)\*

\*M. Sozet et al., Opt. Lett. 40, 2091 (2015)

## Improvement of laser damage resistance

Optimization of E-field distribution

The theoretical LIDT of a component can be obtained from the knowledge of the E-field distribution and LIDT of materials

![](_page_39_Figure_3.jpeg)

#### Significant improvement can be obtained with optimization of the E-field distribution

![](_page_39_Figure_5.jpeg)

#### Optimization of 45° broadband HRcoatings.for Appolon 10PW laser project\*

\*A. Hervy et al., Opt. Eng., to be published

LIDT of broadband reflective mirrors :R>99%,  $\Delta\lambda$ >250nm (S) / 160nm (P) Tests at 800nm, 40fs, 5kHz\*\*

\*\*A. Hervy, PhD thesis, 2016

## Improvement of laser damage resistance Post processing

Laser conditioning or thermal annealing can significantly enhance the LIDT

![](_page_40_Figure_2.jpeg)

Specific treatments can mitigate (arrest) laser damage growth

![](_page_40_Picture_4.jpeg)

2mm

Improvement of LIDT on the surface of fused silica optis at 355nm, 3ns, with isothermal annealing at 1050°C for 12h\*

\*T. Doualle et al., J. Appl. Phys. 119, 213106 (2016)

Example of CO<sub>2</sub> laser processing of damage on fused silica for the Laser MegaJoule project\*

\*T. Doualle et al., Submitted

## Conclusions

The physics of laser damage in the sub-picosecond regime is quite well understood

- Intrinsic performances of optical materials can be ranked based on their bandgap and scaling laws can be derived
- Consequently theoretically high laser damage threshold optics can be designed based on available materials
- However for applications two main points need to be considered and deeply studied:
  - 'Incubation', 'fatigue' or heat accumulation effects of the materials under multiple pulses
  - The densities of growing damage sites related to manufacturing defects and/or contamination
- Post processing techniques that have been applied in the ns regime (annealing, laser conditioning, damage growth mitigation, etc..) could also be of potential interest

## Thank you for your attention!

#### Acknowledgments

![](_page_42_Picture_2.jpeg)

Laser Material Interactions group

![](_page_42_Picture_4.jpeg)

Laser Research Center / Laser Damage group

![](_page_42_Picture_6.jpeg)

CESTA/Laser Damage group, PETAL project, LMJ project

![](_page_42_Picture_8.jpeg)

Laser Components Department

![](_page_42_Picture_10.jpeg)

Apollon project

![](_page_42_Picture_12.jpeg)

Coating department